



PATENT
Customer No. 22,852
Attorney Docket No. 02887.0260

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)	
)	
Takahiro IKEDA et al.)	Group Art Unit: 2878
)	
Application No.: 10/730,921)	Examiner: Le, Que Tan
)	
Filed: December 10, 2003)	
)	
For: METHOD OF SELECTING)	Confirmation No.: 6683
PATTERN TO BE MEASURED,)	
PATTERN INSPECTION)	
METHOD, MANUFACTURING)	
METHOD OF SEMICONDUCTOR)	
DEVICE, PROGRAM, AND)	
PATTERN INSPECTION)	
APPARATUS)	

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

AMENDMENT

In reply to the Office Action mailed October 18, 2005, the period for response to which has been extended through February 20, 2006 (February 18, 2006, being a Saturday and February 19, 2006, being a Sunday), by a petition for a two month extension of time, Applicants amend this application as follows:

Amendments to the Specification begin on page 2 of this paper.

Remarks begin on page 3 of this paper.